

# ELECTRO- AND CHEMICAL- POLISHING NB CAVITIES

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## Abstract

Standard treatments to achieve excellent high rf power Nb accelerator cavities include electro polishing (EP), buffered chemical polishing (BCP), and ~120°C UHV baking (LTB). Those treatments change for RRR>100 Nb: rf residual losses  $R_{res}$ , BCS rf losses  $R_{BCS}(T)$ , low field Q- (LFQ), medium field- (MFQ) or high field- (HFQ) Q slope. Those differences between BCP, EP and LTB are related to differences in oxidation where  $Nb_2O_5$  grows on Nb,  $O^{2-}$  is drawn through the double layer and through  $Nb_2O_5$  injecting O into the open Nb lattice nucleating  $Nb_2O_5$  crystallites straining the  $NbO_x/Nb$  interface heavily worked out below which gives the first consistent explanation for the superiority of EP over BCP and the reasoning for the advantage of LTB. For example by EP and LTB strong O built up and O precipitation at Nb surfaces is found being demonstrated by  $H_{c3}$  increases and by HFQ reductions. By BCP the repeated  $Nb_2O_5$  crystallite growth creates dislocations and injects O into larger Nb depth enforcing weak link (WL) growth, i.e.  $R_{res}$ , MFQ and HFQ are enforced.

## INTRODUCTION

Standard treatments to achieve excellent high rf power Nb accelerator cavities are: high pressure water rinsing (HPR), electro polishing (EP) more than 50 $\mu$ m Nb, buffered chemical polishing (BCP) more than 100 $\mu$ m Nb, and ~120°C UHV baking (LTB) [1-5], which change the rf residual losses  $R_{res}$ , the BCS rf losses  $R_{BCS}$ , the low field Q-drop (LFQ), the medium field Q-drop (MFQ), the high field Q-drop (HFQ), the impedances  $Z(T>T_c, \omega<MHz, B_{dc})$  up to depth of 50 $\mu$ m and the ratio  $H_{c3}/H_{c2}=\tau_{32}>1.69$ . BCP, EP and LTB mainly differ in details of the oxide removal and the oxidation process, especially in strain relaxation and O precipitation, being summarized below.

The quality factor  $Q_0=G/R$  is given by  $G^H$  containing the current distribution and  $R^H$  containing material properties

$$R^H(T, \omega, H) = R^H_{res}(\omega, H) + R_{BCS}((T \leq T_c/2, \hbar\omega \leq \Delta/30) = R^H_{res}(\omega, H) + r_0 \omega^\beta \exp(-\Delta/kT)/kT; \quad (1a)$$

This ansatz and the BCS theory for oxidized Nb fits excellently the T- and  $\omega$ - dependencies of  $R^H(T, \omega)$  of oxidized Nb cavities with averaged values  $r_0$ ,  $\beta$ , and  $\Delta/kT_c$  for a  $\lambda_{BCS} \sim 100$ nm penetration layer changing with oxidation for RRR>100 Nb in characteristic ways [1-8]. By the weak interaction with phonons locally confined quasiparticles  $|e| \leq \Delta_{ave}$  are easily driven out of thermal equilibrium yielding a saturating loss component named low field Q-slope (LFQ) [2b,5]

$$R_s(T, B > 10 \text{ mT}) = a(T)/B^2 + R_{BCS}(T, \sim 20 \text{ mT}) + R_{res} \quad (1b)$$

whereas extended  $|e| \geq \Delta_{ave}$  rf quasiparticles have long mean free path  $l_{in} = v_F \tau_{in}(T, < 10 \text{ GHz}) > 6 \cdot 10^{-3} (T_c/T)^3 \text{ cm}$  and so  $R_{BCS}$  does not heat its surface. At  $Nb_2O_5/Nb$  interfaces

via localized states  $n_L \leq 10^{21}/\text{cm}^3$  rf shielding current momenta are transferred to the lattice coherently

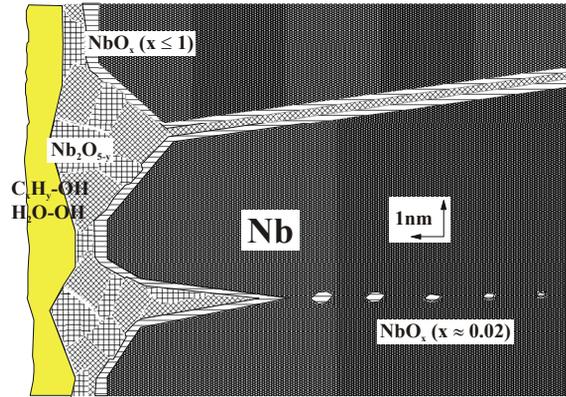


Figure 1: Nb surface with crack corrosion by wet oxidation by  $Nb_2O_5$  volume expansion (factor 3).  $Nb_2O_5$ - $\gamma$ - $NbO_x$  weak links/segregates ( $y, x < 1$ ) extend up to depths between 0.1– 1/1-100  $\mu$ m for good/bad Nb quality and weak/strong oxidation [8-11]. The double layer (OH) $_y$ H $_2$ O being chemisorbed by hydrogen bonds to  $NbO_x$  may be covered by  $(C_xH_yOH)_yH_2O \geq 3$ nm and dust.

$R^{PH}_{res}(T, \omega) = \{e\mu_0\omega\lambda_{BCS}(T)\min[l, \lambda_{BCS}(T)]n^2_L/v_F\}^2/\rho v_T$  (2a) with  $\rho$  as density, with  $v_T$  as transversal sound velocity and with  $l_s \sim 3$ nm as surface mean free path of Nb causing  $R^{PH}_{res} \leq 10^{-9} \Omega(f/GHz)^2$  by phonon generation. At  $Nb_2O_5$  serrations in Fig.1  $n_L$  cause weak links (WL) losses  $R^{WL}_{res}(T, \omega) \geq 1n\Omega(f/GHz)^2$  (2b) being obvious in cold worked or thin film Nb cavities [4a,8].

Field dependent losses  $R^H(T, H)$  can be written as Taylor series with the first two terms named MFQ  $\delta R^B = R^1_{hys}(T, \omega)H/H_c + R^H(T_0, \omega, H)\gamma(T)(H/H_c)^2 +$  (3a)

by Josephson fluxons penetrating fast above  $H_{c1J}$  into WLs yielding the fluxoid hysteric losses  $R^1_{hys}(T, \omega) H/H_c = 4/3\pi\omega |H - H_{c1J}|/2j_{cJ}(T)2\lambda(T)$  [2b,3,5,8]. As consequence  $R^{WL}_{res}$  and  $R_{hys}$  heat the surface enhancing  $\gamma$   $R_{BCS}(T+\Delta T) = R^H H^2/2\{1 + \gamma^*(T)(B/0.2T)^2 + \dots\}$  (3b)

According to [5] HFQ is based on pair breaking caused by Ecosot with  $E > MV/m$  acting at localized states  $n_L$  in  $Nb_2O_5$  with an energy gain  $2zE > 1$ meV above the energy gap  $2\Delta^*$  being described quantitatively by  $R^E(E) = b_s B^2/E^2 s(-c/E, -c/E^0) \sim b^*(\exp(-c/E) - \exp(-c/E^0))$  (4) being dominated by crystallographic shear planes (CS) bordering crystallographic blocks (CB) with their low  $\Phi_s = 0.1$ eV, i.e.  $\kappa_s = 1.6/\text{nm}$ , yielding  $c_s = 2\kappa\Delta\epsilon/e\beta^* = 130 - 400$  MV/m by  $\Delta \sim 1.5$  meV and by  $\epsilon_s = 20$  [5,10a]. In contrast to the qualitative model in [2b] the pair breaking  $ezE \geq \Delta$  is treated in [5] yielding the HFQ source term  $b_s(E)$ , feeding the HFQ valve and HFQ-BCS loss terms the latter defines  $Q_0$ . In Figs.2  $Q_0$  drops by more than a factor 10 without rf break down by  $l_{in} > mm$  of BCS

quasiparticles and  $b_s(E)$  fits observation with a correlation factor  $r^2 > 0.98$  [5].

## NB OXIDATION

The improved understanding of Nb oxidation is based on older [10] and on recent surface science results [7,9,11] summarized below explaining differences between EP- and BCP- Nb removal [9c]. Tunnelling [12], ARXPS [10-11e], x-ray studies [11e,f], positron annihilation [11f] and  $Z^H(T,H)$  [10] indicate gross differences between different  $Nb_2O_5/NbO_x/Nb$  surfaces.

As **first step in oxidation**, O dissolves atomically in the open Nb lattice and migrates along grain boundaries and dislocations into the interior. Below about 500K as a **second oxidation** step the Cabrera Mott growth of  $Nb_2O_5$  is based on the binding energy potential  $V_m^O \approx 0.6V = b(O-O)-b(Nb-Nb)$  causing electrons  $n_c$  to tunnel through  $Nb_2O_5$  charging O chemisorbed from lab air or vacuum. This yields electrochemical like  $Nb_2O_5$  growth where  $V_m^O$  drives mainly (~80%) O ions through  $Nb_2O_5$  toward the metallic  $NbO_x(x \leq 1)$  surface to be discharged there and being injected into the Nb lattice or nucleate as CBs separated by CSs [10] needing a factor three larger volume straining the interface. At interfaces the surplus O and the  $Nb_2O_5$  strain are relaxed in soft Nb by O injection and by creation of dislocations channelling O locally deep into Nb showing up, e.g. as crack corrosion in Fig.1. O precipitates under volume expansion in Nb as metallic  $Nb_6O$  or  $NbO_x(x \leq 1)$  plaques or as dielectric  $Nb_2O_5$  preferably at defects eased by ~100°C in LTB.

In *wet oxidation* the potential  $V_m = V_m^O + V_d$  acts between the Nb/ $NbO_x$  metal and the charged NbO-OH- $H_2O$  double layer with its dipole potential  $V_d$ . This watery interface eases the  $O_2$  ionisation and  $O^{2-}$  uptake into  $Nb_2O_5$  where  $V_m$  results in fast transfer of  $O^{2-}$  along CSs via  $V_{OS}$  toward the  $NbO_x$  surface. In *BCP* a 4nm thick nano crystalline  $Nb_2O_5$  grows repeatedly which by the volume increase above a factor 3 strain the Nb surface repeatedly and strongly. The localized strain is relaxed by local O injection and by dislocations creation yielding O transfer into larger depth <50 $\mu m$ . In *EP Nb is oxidized under potential control* (~0.7V) [11d] to  $Nb^{5+}$  ions dissolving in HF directly without strain by  $Nb_2O_5$  crystallites. Hence in EP less dislocations are created transferring O into larger depth, i.e. most of the O surplus sticks at the surface. *Dry oxidation* of Nb with small dislocation densities, e.g. after annealing above 1000°C, is governed by an ordered, thin CB layer ( $\leq 1nm$ ) [11e] with  $\Phi_B \sim 0.6eV$  [10a,12a,b]. Hence, the charging of chemisorbed  $O_2$  and the transfer of  $O^{2-}$  are slow resulting in slow  $Nb_2O_5$  growth ending at  $d_0 \sim 1-2nm$  and the reduced strain acting onto the interface reduces the dislocations creation, i.e. reduced O migration away from the surface. By defects dislocations or impurities CSs get nucleated as second layer and there  $V_m^O$  acts highly local.

*The (UHV) baking at 120°C* (LTB) eases relaxation of defects yielding a reduction of  $n_L$  in  $Nb_2O_5$  [10a,b,11e] and of dislocations in Nb [7] and expansive precipitation

of  $Nb_2O_5$ ,  $Nb_6O$ , and  $NbO_x$  out of the O lattice gas shifting H further into Nb [11i] with negligible O transfer from the oxide as measured by x-ray and SIMS [11f]. The LTB precipitation yields an  $NbO_x$  interface layer with 7.6 at% O in the first 10nm, i.e. reduced surface mean free path  $l < 2nm$  [11e] instead of 3.6 at% O by room temperature air oxidation. By dissolution of the 2 – 4nm thick LTB oxide and afterwards wet oxidation (HF) about 2nm Nb with its precipitates are transferred to the wet oxide (~4nm) with less precipitates behind.

## SUPERCONDUCTIVITY OF OXIDIZED NB

Clean superconducting (sc) Nb [10] shows  $T_c = 9.25K$  and  $\Delta_0/kT_c = 2.05$  degrading by O pick up, where 2at% O in solid solution degrades  $T_c$  and  $\Delta$  by 20% and the mean free path  $l$  to <8nm whereas the d-bonded precipitates  $Nb_6O$  or  $NbO_x(x \leq 1)$  act more strongly on  $l$  but less strongly on  $T_c$  and  $\Delta$  as shown, e.g. by  $\Delta \sim 0$  for disordered  $NbO_x(x \sim 1)$ . The d-bonded  $Nb_2O_5$ ,  $Nb_6O$  or  $NbO_x(x \sim 1)$  may precipitate out of atomically dissolved O at nuclei under volume expansion.

*Tunnelling* through  $Nb/NbO_x/Nb_2O_5/NbOOH/H_2O$  yields via leakage currents more than a factor 100 variations in  $n_L(z) \leq 10^{21}/cm^3$  with oxidation [12a,b], yields via  $I(U)$  normal conductivity for a *1.5nm thick surface layer* [12c] and the  $T_c^* \sim 7K$  phase at interfaces [12d] confirmed by  $Z(T, \omega < MHz)$  [9d]. Information on the *upper 100nm Nb* is given by  $R_{BCS}(T, \omega, H)$  in its  $T$ ,  $\omega$  and  $H$  dependencies. For example, BCP wet oxidation yields for large grained Nb a  $\Delta_{ave}/kT_c$  reduction down to 1.7 and for small grained or defective, e.g. cold worked Nb, down to ~1.8. The latter observation is explained by precipitation of O at nuclei. Those precipitates smear the energy gap by  $\Delta^* \leq \Delta_{ave}$  plaques reducing  $R_{BCS} (< 15GHz)$  shown by  $\beta (< 15GHz) \sim 2$  in Eq.(1a) [4b] and enforcing LFQ in Eq.(1b) [4a]. The amount of O in the upper 100nm is in excess of 2at%, i.e. 20% gap reduction, as shown by  $R_{BCS}(T, l < 8nm)$  fits yielding  $\Delta_{ave}/kT_c \geq 1.7$ . As precipitate this amount relates: to the  $T_c^* \sim 7K$  phase found by tunnelling [12d], by  $Z(T \sim T_c^*, \omega < MHz, H_{dc})$  jumps [9a,d], by  $r_{32}$  increases [9b,c] or by the coherent onset ratio  $H_{c3}^{coh}/H_{c3} \sim T_c^*/T_c$  in [9b,c]. By surface physics means 3.6 at% O by room temperature air oxidation grows by LTB to 7.6 at% O in total amount in the first 10nm [11e], the latter is related to precipitation without long distance diffusion in line with [11f] and with ordering reducing the density of  $n_L$  [5] or of dislocations [7]. In BCP the repeated straining by  $Nb_2O_5$  crystallites is relaxed by repeated O injection and by repeated dislocations creation [7] channelling O away from the surface into larger depth, hence  $r_{32}$  increases by about 10%, only [2,5,9], *longer Nb<sub>2</sub>O<sub>5</sub> filled weak links* (WL) are created enhancing  $R_{res}$ ,  $R_{hys}$  and MFQ, pinning sites occur up to depths of 50 $\mu m$  found by low frequency impedance measurements in the super-conducting state [9]. As discussed above, in *EP the continuous injection of O into Nb* with only one final wet oxidation results in less

strain, i.e. less dislocations channelling O away from the surface, and so O sticks to surface resulting: in  $r_{32}$  increases by about 20%, in weakened HFQ,  $R_{res}$ ,  $R_{hys}$  and MFQ and in reduced pinning up to depths of 10 $\mu$ m found [9c]. In both cases by LTB O precipitates at the surface: enhance

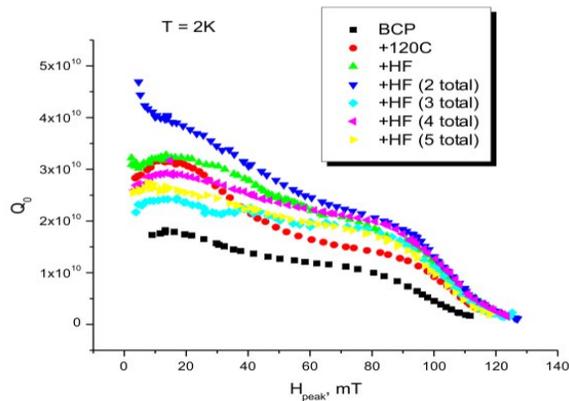


Fig.2a: Q(2K,1.3GHz,H) of fine grained, BCP stripped Nb, treated by LTB and several HF stripping.

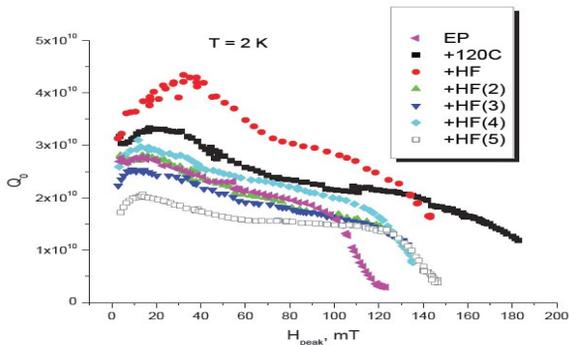


Fig. 2b: Q(2K,1.3GHz,H) of fine grained, EP stripped Nb, treated by LTB and several HF stripping.

$R_{BCS}(4.2K, <15GHz)$ , enhance  $\Delta_{ave}/kT_c$  to 1.85-1.9 in Eq.(1a), enforce LFQ in Eq.(1b) [2b,5], reduce  $l_s < 2nm$ , enhance  $r_{32}$  by about 10% [9], whereas  $b_s$  in Eq.(4) is reduced by several orders of magnitude [5].

### DISCUSSION

Above it has been clarified that the main differences between BCP- and EP- oxidative Nb removal is the repeated Nb<sub>2</sub>O<sub>5</sub> crystallite (~4nm) growth in BCP, which causes repeated strain and O injection causing repeated dislocation creation channelling O away from the surface deep into Nb as shown: by WL growth enforcing  $R_{res}$ ,  $R_{hys}$  and MFQ [1], by severe HFQ, by little  $r_{32}$  increases and by enforced pinning up to depth of about 50 $\mu$ m [9]. In the case of EP, fewer dislocations, i.e. fewer WLs, are created and O stays at the surface enhancing  $r_{32}$  and reducing HFQ and  $R_{res}$ ,  $R_{hys}$  and MFQ. By LTB, O precipitation is enforced at the surface enlarging  $r_{32}$ ,  $R_{res}$ ,  $R_{hys}$  and MFQ but weaken HFQ [5]. Aside of defects created by oxidation, defects may be there from the beginning as in the case cold worked Nb [5] with enforced WL growth in

oxidation enhancing:  $R_{res}^{WL}$ ,  $R_{hys}^1$  and MFQ showing up in  $\Delta Z$  increases [9a,c].

Whereas it is well accepted that EP results in better Nb cavities then BCP shown clearly in [1], the surface physics behind those findings is modelled here for the first time. Whereas by BCP in Fig.2a  $R_{res}$  is only slightly enhanced over  $R_{res}$  of cold worked Nb [5] the HFQ onset is shifted in this cleaner and smoother Nb to much higher fields but still EP data in Fig.2b show further improvement of  $R_{res}$ ,  $R_{hys}$ , MFQ and HFQ. By LTB  $R_{res}$ ,  $R_{hys}$ , MFQ weaken, LFQ strengthens and HFQ improves especially for EP surfaces. By HF stripping of the dielectric LTB oxide coating and wet oxidation afterwards the O precipitate rich region is replaced by cleaner Nb [11e] therewith LFQ is reduced and  $R_{res}$ ,  $R_{hys}$  and MFQ improve hinting to the fact that those locally confined quasiparticles  $|\epsilon| \leq \Delta_{ave}$  and WLs grow in density toward the LTB surface in line with the O concentration in [11e]. With further HF stripping HFQ reappears where  $Q_0$  is defined by HFQ BCS loss term with its long mean free path not heating the surface, i.e. not causing thermal runaway.

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